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Xilinx SSI Technology Concept to Silicon Development Overview

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Aug 27th, 2012

Agenda

➤ **Economic Drivers and Technical Challenges**

➤ **Xilinx SSI Technology, Power, Performance**

➤ **SSI Development Overview**

➤ **Summary**

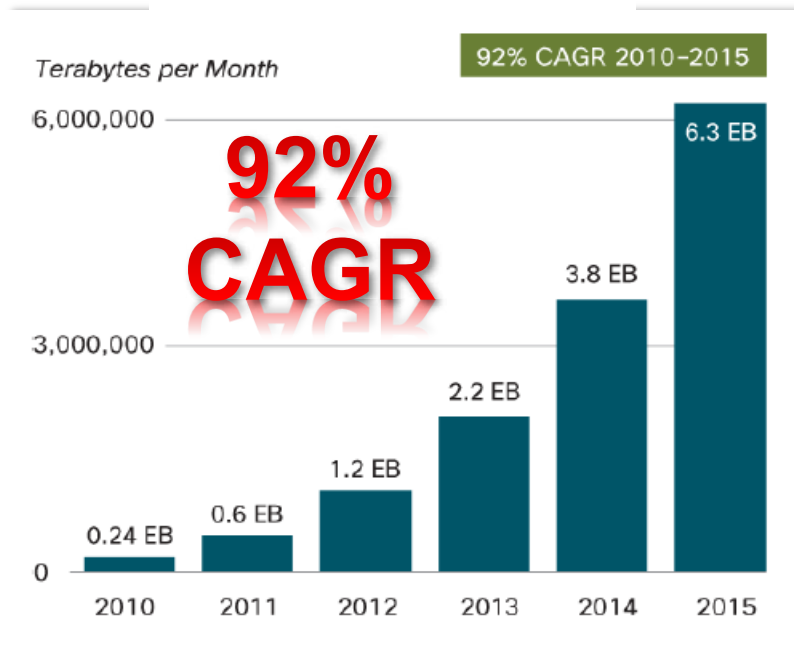
Market Dynamics

Video Driving Explosive Growth in Traffic
By 2015 2/3 of Mobile Traffic will be Video

Machine to Machine

- **Smart Meters, Security Cameras, Health Care, Telematics, etc.**

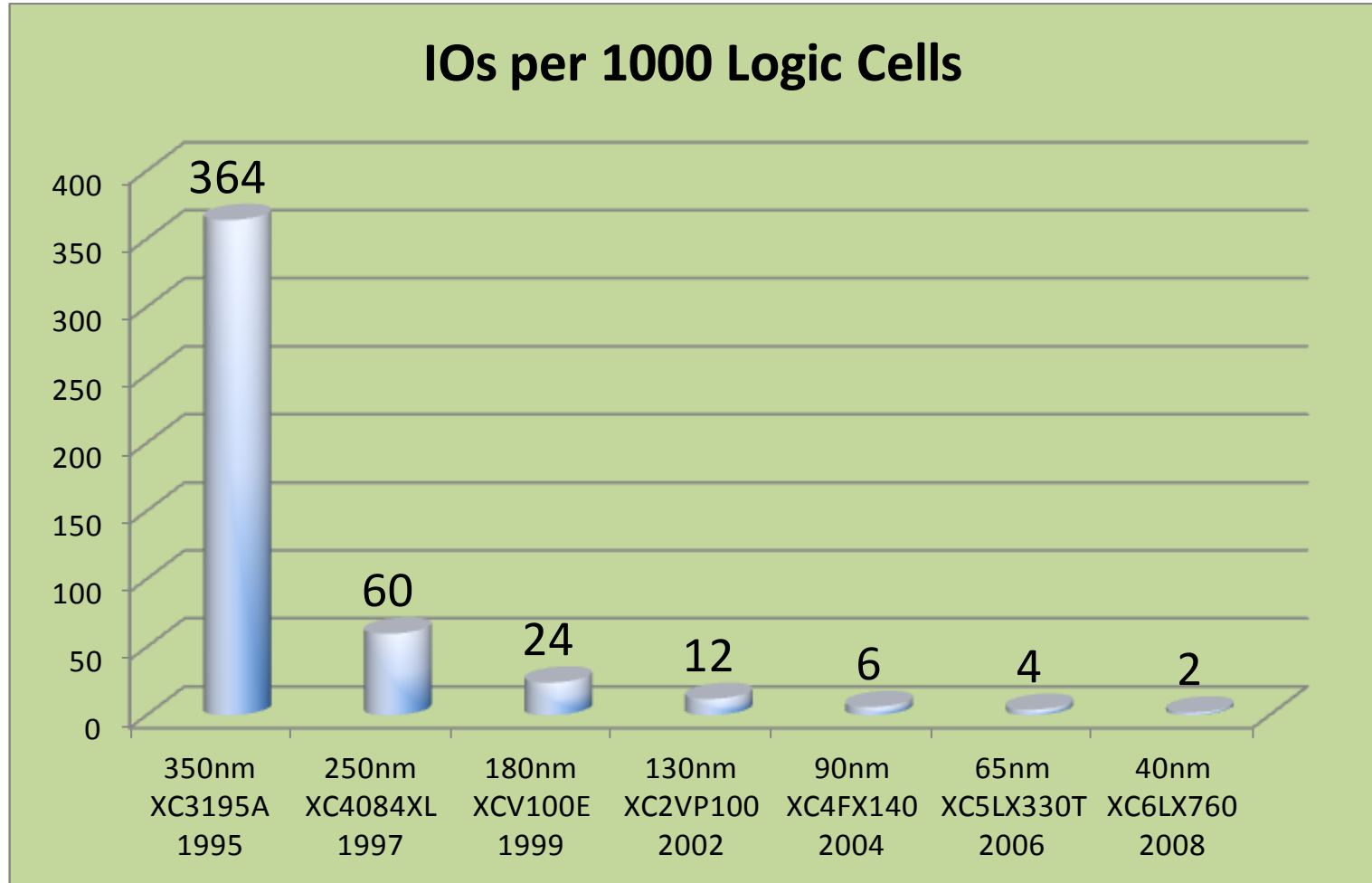
Mobile Data Traffic



**2x Bandwidth growth every 3 years
at the SAME POWER BUDGET**

On Die I/Os Not Scaling

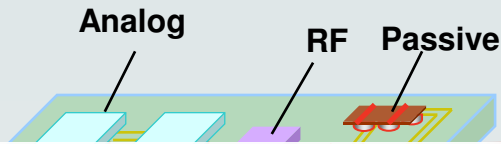
Number of I/Os per 1000 logic cells in the largest FPGA in each family



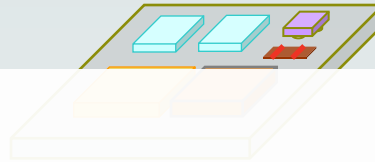
Logic doubles with Moore's Law but I/O quantity does not

The Progression of 3D Technology

Traditional MCM/PCB



Silicon Interposer 2.5D



Full 3D



Goals for 2.5D / 3D

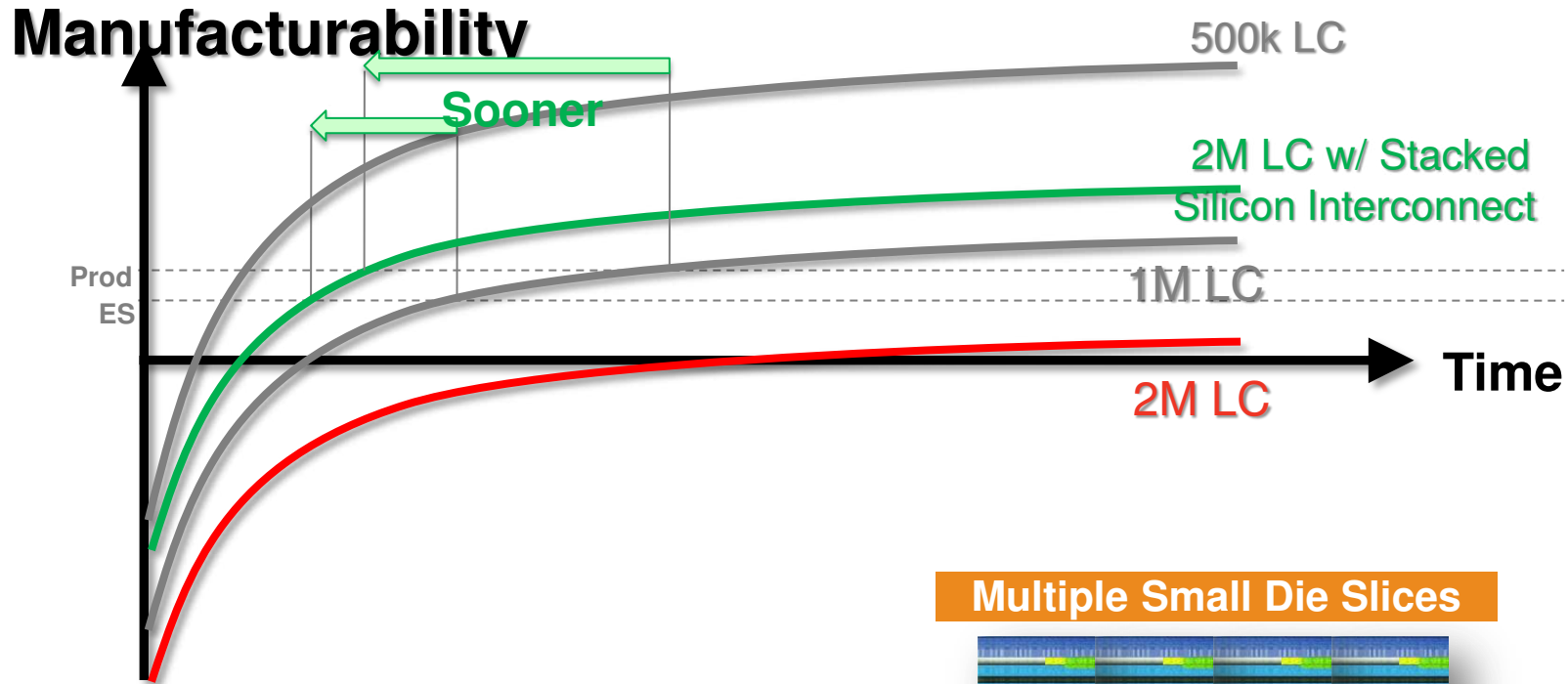
- **Connectivity: Break die to die IO bottleneck**
- **Capacity: Achieve Integration beyond Moore's Law**
- **Power: Reduce Total Power**
- **Heterogeneous SOC's: Mixed Functions & Processes**

Flipchip + wire bond

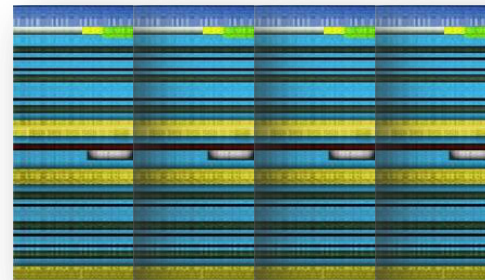
2.5D side-by-side integration
on a silicon interposer

Vertical stacking with
memory & logic

Capacity : Beyond Moore's Law



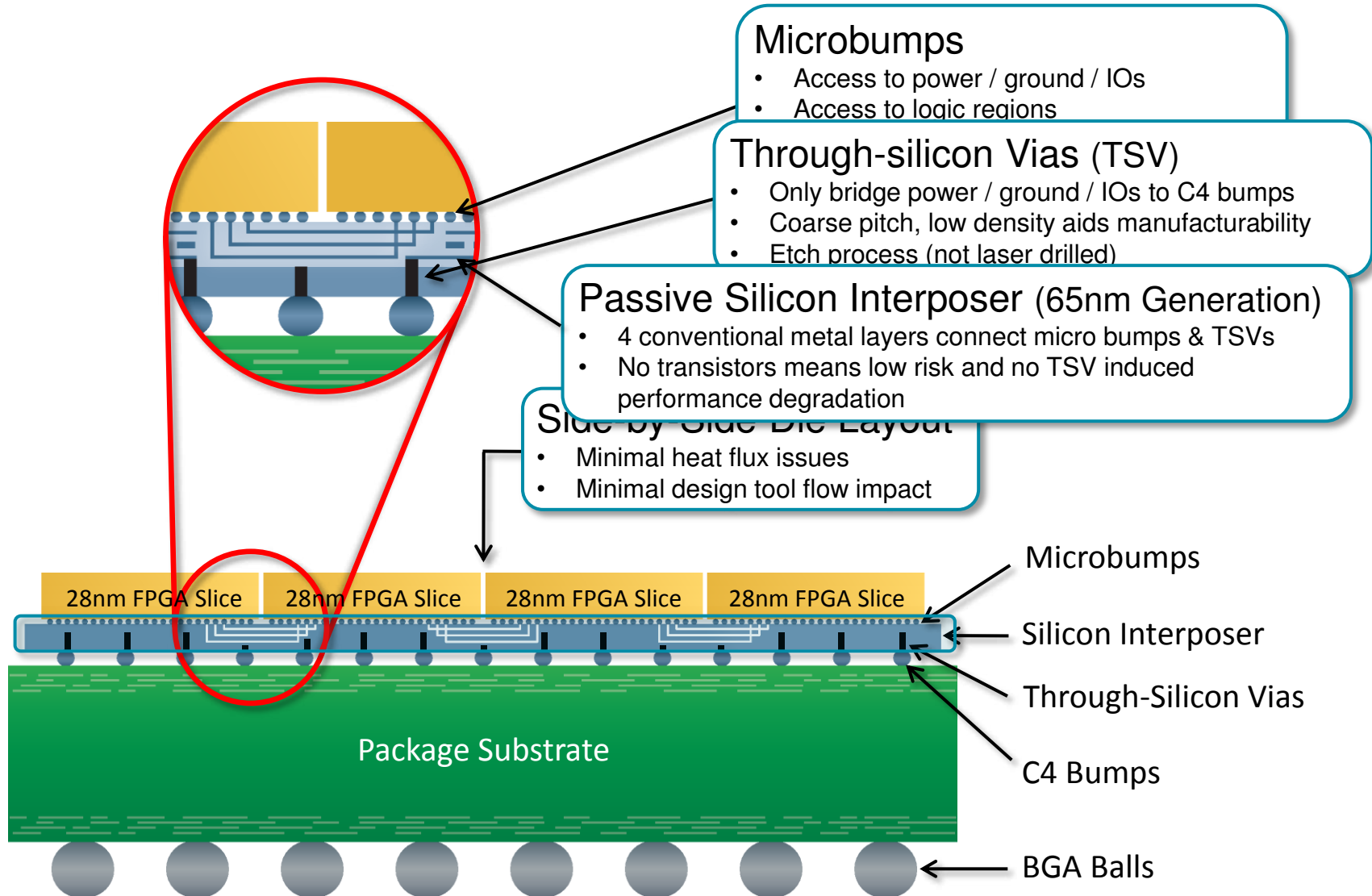
Multiple Small Die Slices



✓ Greater capacity, faster yield ramp

Reference:
Node N to N+1 ~ 1.5 to 2 years for Xilinx FPGAs

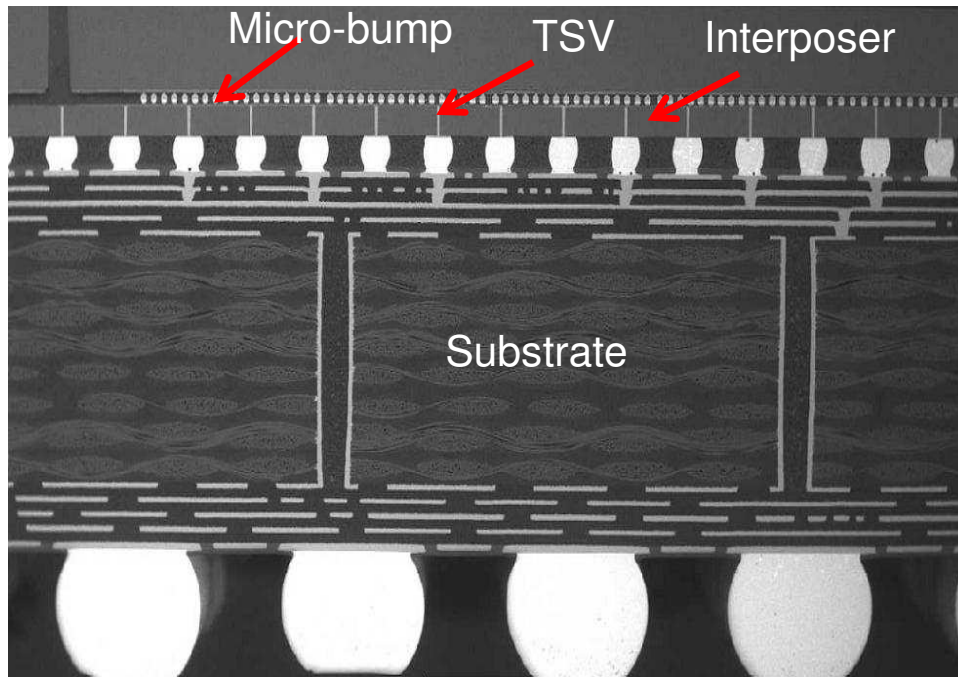
Well published technology boiler plate



Cross-section of 28nm FPGA with SSI

Virtex-7 2000T

28nm Active Die + 65 nm Passive Interposer



Courtesy of Xilinx, TSMC, Amkor

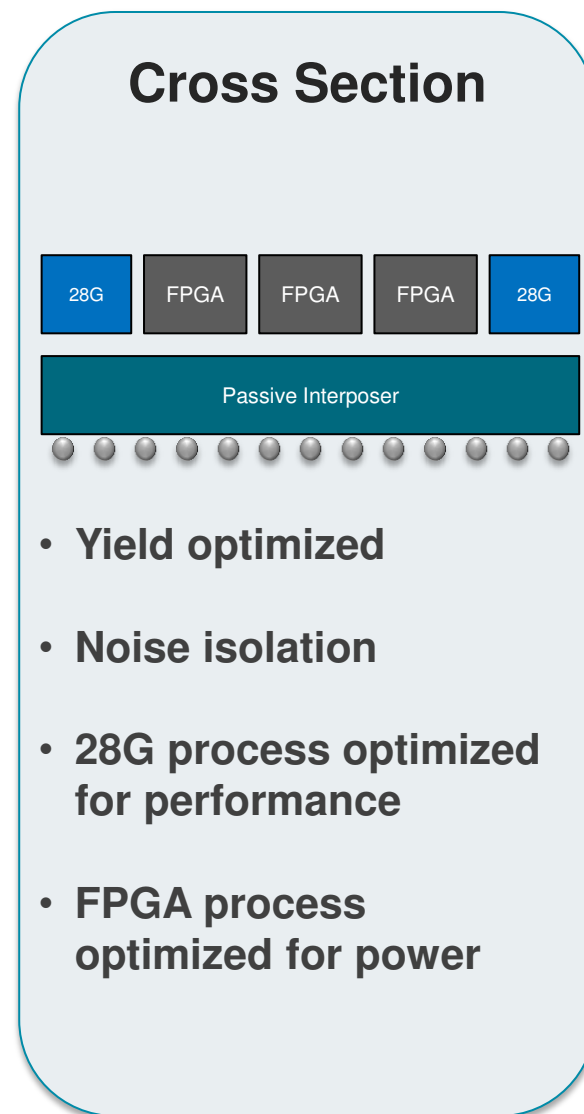
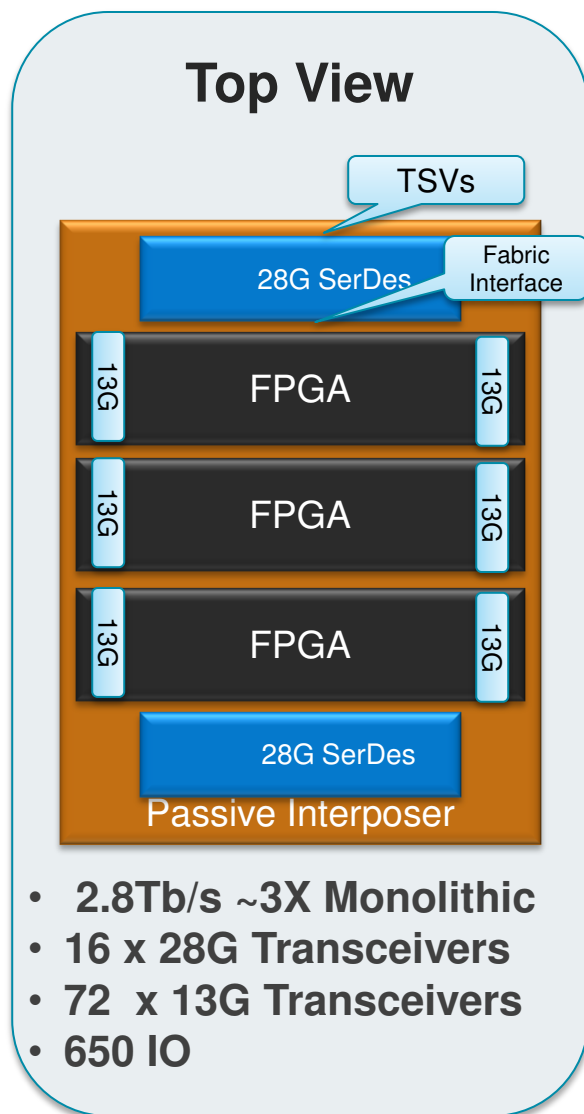
Interposer /Package Technology

Technology	Specs
M1-M4	2um pitch 4 4X layers
TSV	12um diameter & 180um pitch
Micro-bump	45um pitch
C4	180um pitch
Package	6-2-6 Layer, 1.0 mm BGA pitch

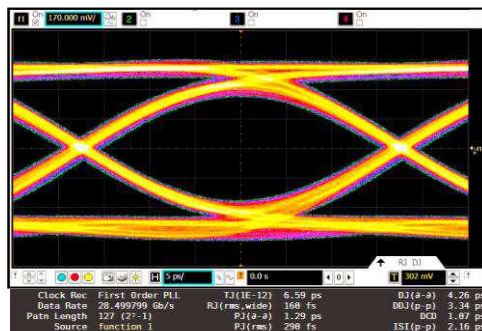
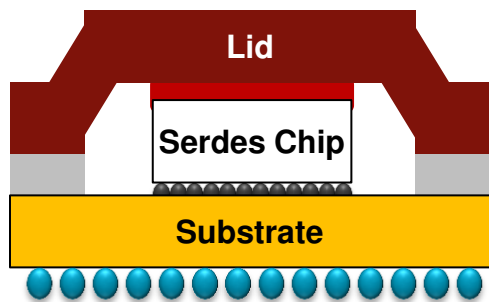
- Low risk approach to integrate TSV & u-bump
- High density micro-bump for ~50K chip-to-chip connections
- Better FPGA low-k stress management with silicon interposer

Heterogeneous FPGAs with SSI

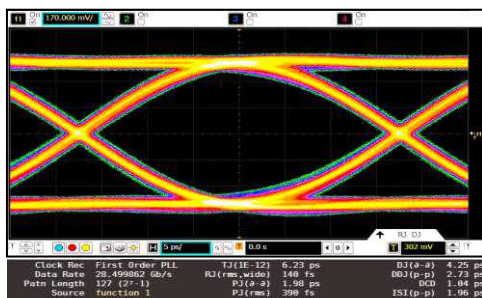
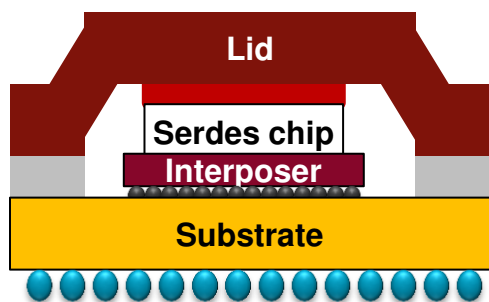
Virtex-7 HT



2.5D Performance vs. Monolithic



Vehicle 1 - Monolithic packaged 28Gbps Serdes



Vehicle 2 - 2.5D packaged 28Gbps Serdes

➤ Measurements show 2.5D comparable performance to Monolithic die

➤ Diagrams not drawn to scale

Reduced noise and better performance margin with SSI

2.5D / SSI Takeaways

➤ SSI Technology summary

- Capacity beyond Moore's law, Faster yield curve
 - Breaks die to die IO bottleneck
 - Heterogeneous SOCs
 - Power advantage
-
- Stepping stone to true 3D



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SSI Implementation Overview



Challenges for 3D design and validation

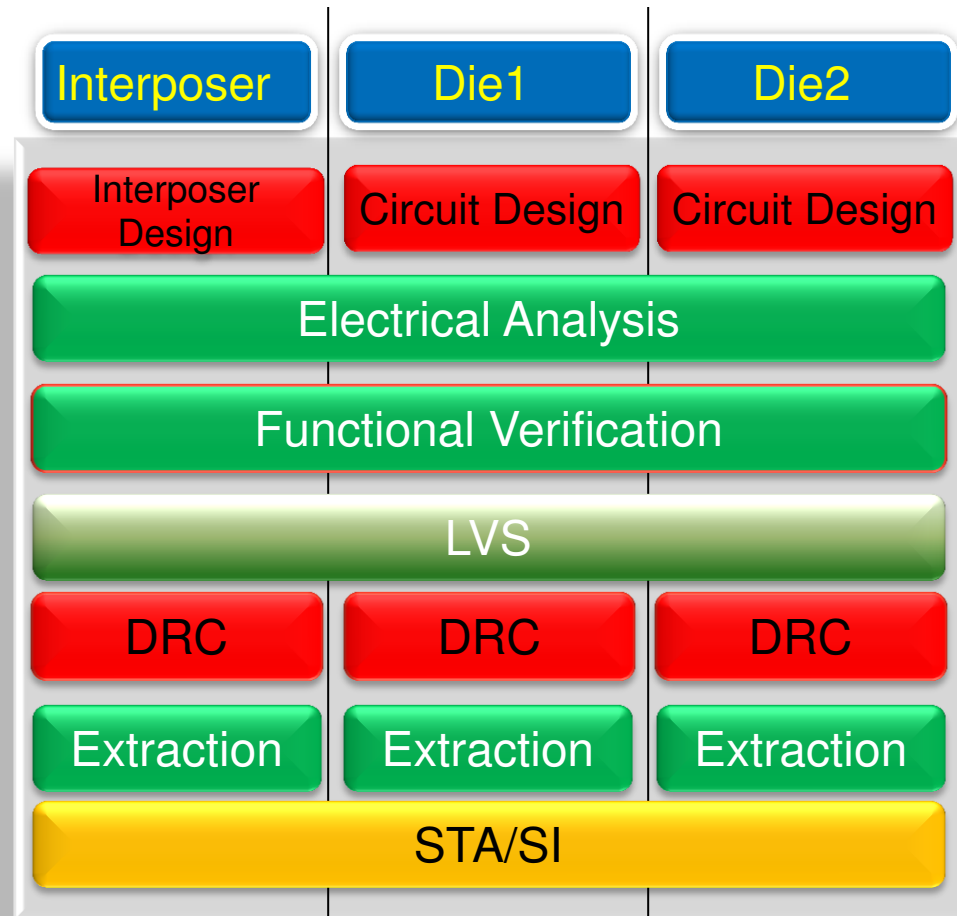
➤ What areas of design validation and sign off are challenging for 3D and why?

- Circuit Design and Schematic capture
- RTL, Physical Design of Top Die and Interposer
- Extraction
- Functional and Physical Verification (LVS, DRC)
- Chip level functional verification
- STA
- IR/EM/SI or other Electrical analysis
- Assembly and Yield (beyond the scope of this presentation)

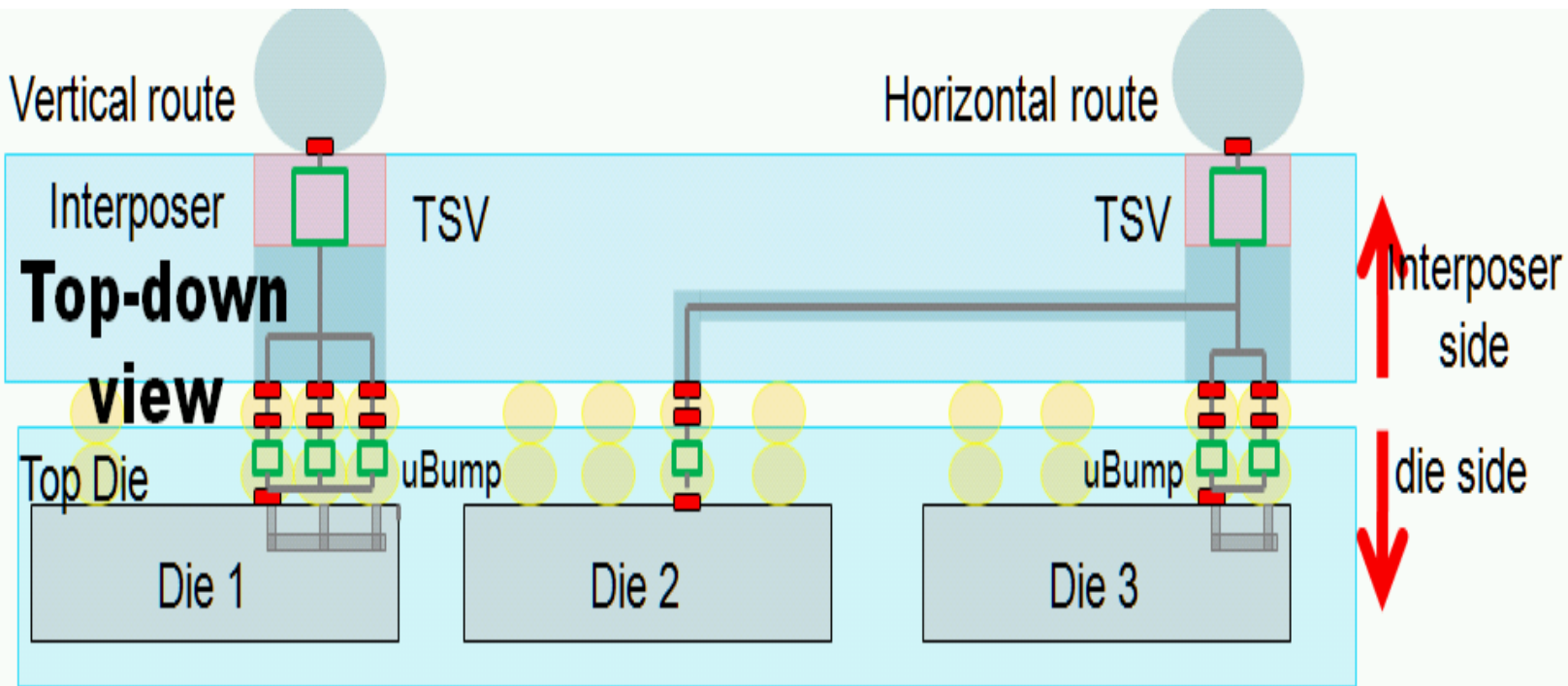
Analysis and Sign off

State of EDA tools

1. Can the analysis be split into hierarchical independent levels?
2. Can the data for analysis be split into hierarchical independent levels



SSI Full chip



Circuit and Physical Design

➤ Circuit Design and Schematic capture

- Electrical modeling of Interposer
- Design of driver and receiver
- HSPICE Simulations with process models from multiple process nodes
- Signal Integrity analysis
- ESD considerations

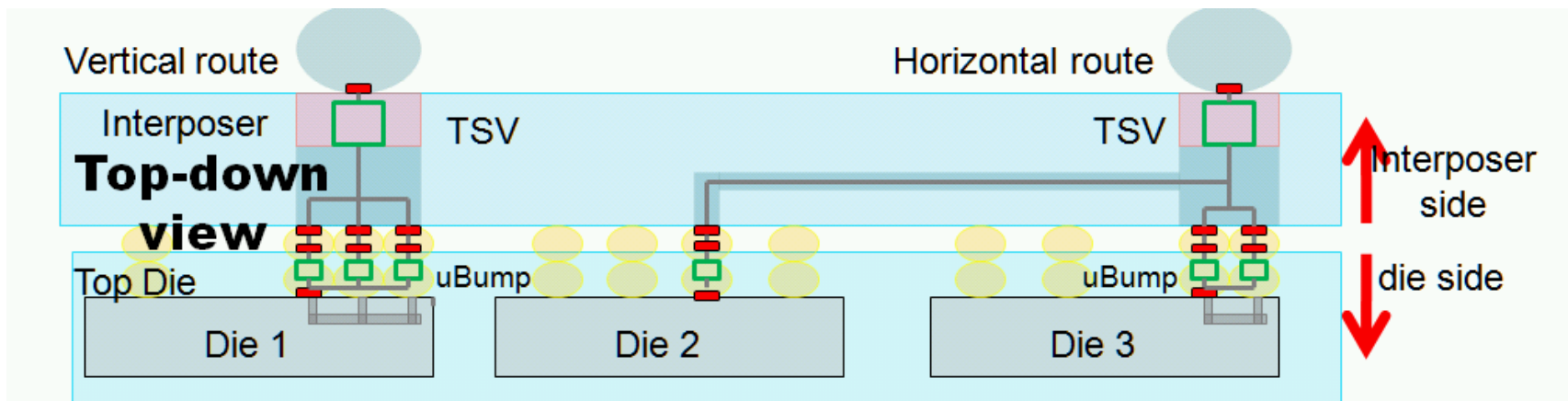
➤ Physical Design, Extraction and Verification

- Manual vs. Auto-routed Interposer
- Like Top Die (e.g. all FPGAs) vs. unlike Top die (FPGAs, w/ 28G SerDes)
- Extraction of Interposer layout
- LVS done on each Top die and multiple die together;
- DRC done on Interposer and Top Die separately

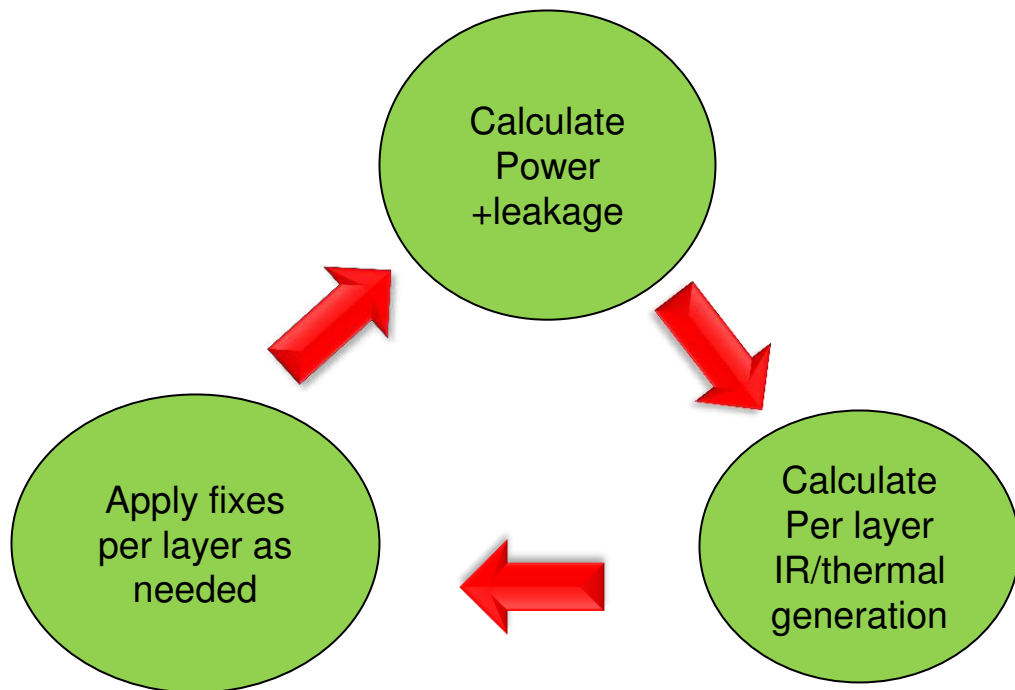
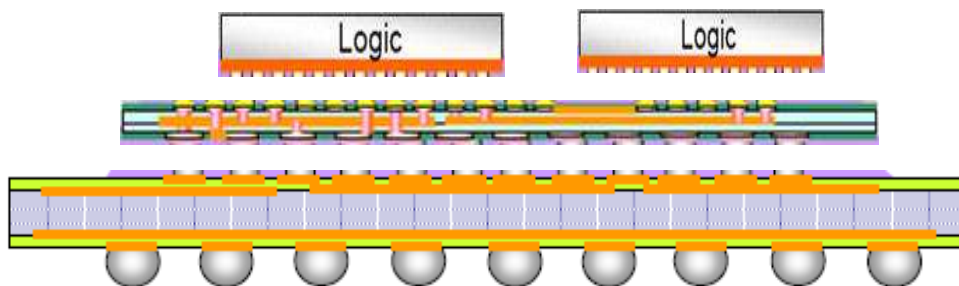
Static Timing Analysis

➤ STA

- Black box ILM generated for each die
- Full chip netlist (w/ extracted Interposer) generated using internal scripts
- Special consideration given to the process distribution



EM/IR and Thermal Analysis: Challenges

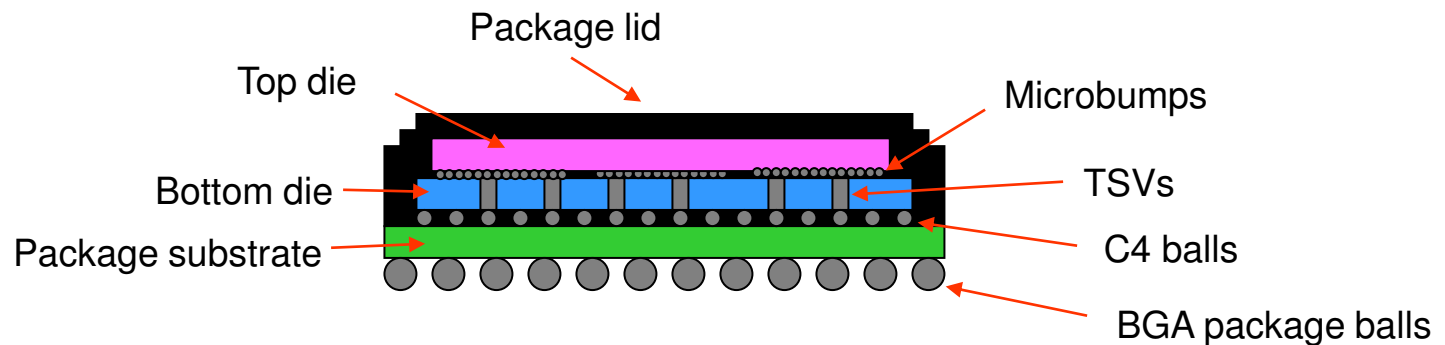
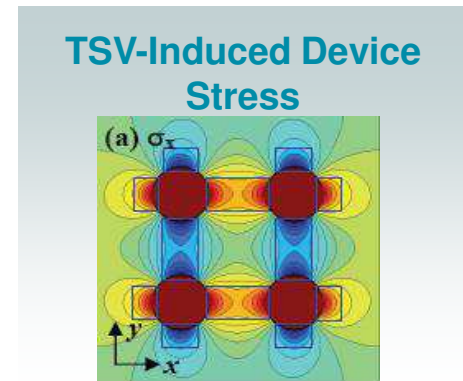


EM/IR by budgeting

Accurate EM/IR and thermal analysis is iterative in stacked Die Scenario.

3D: The next frontier

- Higher performance chip stacked on top
 - Thermal considerations
- Bottom die includes power TSV's for top die
 - Can be in older, "TSV-friendly" technology
- Floor-planning is critical:
 - Thermal concerns (stacked thermal flux)
 - TSV keep out zones may be required in bottom die to avoid stress-induced performance impact



Assembly Technology still evolving

Call-to-Action: Develop & Evolve 3D Standards

➤ Design enablement

- Interposer Models
- EDA Tools for 3D development and verification
- Chip-to-chip interface standards

➤ Manufacturing standards

- DFM rules for TSV, microbump
- Materials: TSV, u-bump
- Thermal budget

➤ Test

- Test HW & u-bump probing
- Known-Good-Die method
- Self Test Required (FPGA programmability is an advantage)

Conclusion

- **Bandwidth, power and cost demands are beginning to present significant challenges for monolithic silicon**
- **Stacked Silicon Interconnect is a breakthrough!**
 - Capacity
 - Connectivity
 - Power, Performance
 - Heterogeneous SOCs

SSI technology is the next big step in IC evolution

Stacked Silicon Interconnect: A World of Difference



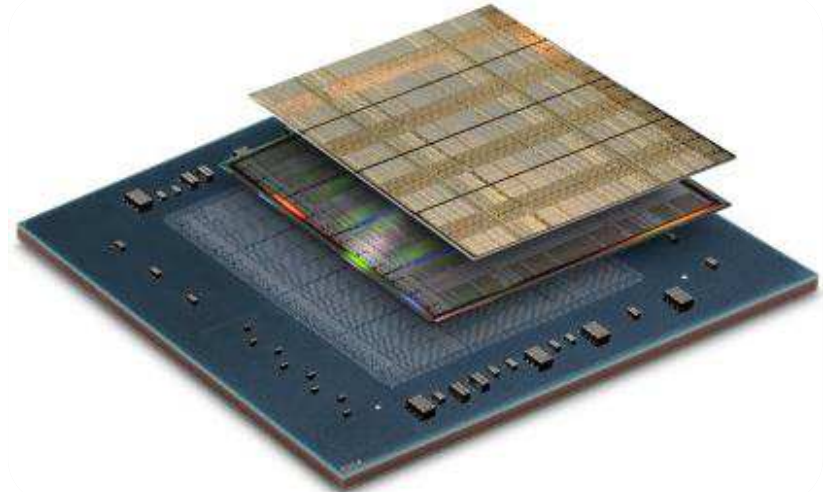
Earth

Area: ~500 Million km²

Population: ~6.8 Billion People

Oceans: 5

Age: 5 Billion Years



Virtex-7 2000T

Interposer Area: ~775 mm²

Population: ~6.8 Billion Transistors

Chips: 5

Age: 40 weeks